

Discrepancy of MIP Peak between 2019 and 2021 Beam Tests

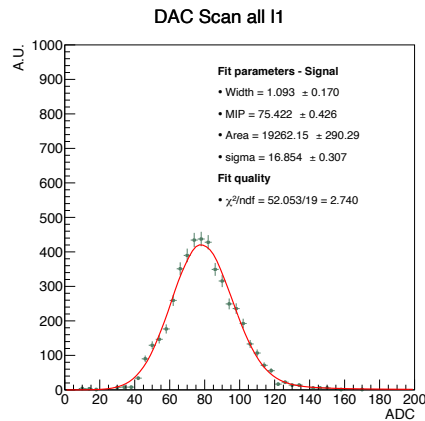
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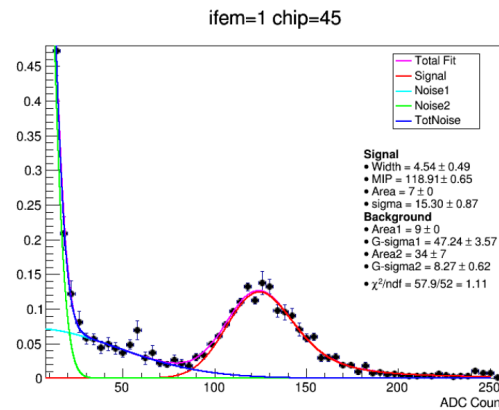
// DAC scan comparison

https://indico.bnl.gov/event/15657/contributions/63079/attachments/40865/68318/INTT_energydeposit_summary.pdf

Testbeam2021, 50 V
Positron beam, 1 GeV



Testbeam2019, 100 V
Proton beam, 120 GeV



2021 Test beam was operated at 50V instead of 100V. However, observed MIP peak position (collected charge) was too low compared to what we expect from theoretical prediction.

$$\frac{MIP_{2021BT}}{MIP_{2019BT}} = \frac{75}{118} \sim 0.63$$

The peaks are different
Original though : because of the difference of the supplied voltage

2019 Beam Test

- RCDAQ. FPHX parameters were operated via expert-GUI.
- I couldn't find the exact records of FPHX parameters for the 2019 beam test though, it is likely FPHXs were operated with default parameters.

No specification in the gain setting. Unless we customize parameters via expert-GUI, FPHX just runs with default parameters (or loaded from a default setting file?)

Default Configuration

Telescope

- Position
 - $x=1570\text{mm}$
 - $y=1500\text{mm}$
- Rotation
 - 0°
- Vertical Tilt
 - 0°

DAC	Threshold Value
0	8
1	16
2	32
3	48
4	80
5	112
6	144
7	176

Beam

- 120 GeV primary proton
- $\sim 10\text{kHz}$
- $\sigma_y \sim 2\text{mm}$, $\sigma_x \sim 6\text{mm}$

Snapshot from the RunPlan of Beam Test 2019

Expert GUI Screenshot provided from Jin Huang
(Typical FVTX Operating Condition)

ROC: NEO Column: 0 Station: 0

Side 0

Side 1

Side 0 Chip Settings [Editable]

Side 0 Controls

Vref	1	1	1	1	1	Vref	1
DAC 0	8	8	8	8	8	DAC 0	8
DAC 1	16	16	16	16	16	DAC 1	16
DAC 2	32	32	32	32	32	DAC 2	32
DAC 3	48	48	48	48	48	DAC 3	48
DAC 4	80	80	80	80	80	DAC 4	80
DAC 5	112	112	112	112	112	DAC 5	112
DAC 6	144	144	144	144	144	DAC 6	144
DAC 7	176	176	176	176	176	DAC 7	176
N1Sel	6	6	6	6	6	N1Sel	6
N2Sel	4	4	4	4	4	N2Sel	4
FB1Sel	4	4	4	4	4	FB1Sel	4
LeakSel	0	0	0	0	0	LeakSel	0
P3Sel	0	0	0	0	0	P3Sel	0
P2Sel	4	4	4	4	4	P2Sel	4
GSel	2	2	2	2	2	GSel	2
BWSel	4	4	4	4	4	BWSel	4
P1Sel	5	5	5	5	5	P1Sel	5
InjSel	0	0	0	0	0	InjSel	0
LVDS Current	7	7	7	7	7	LVDS Current	7
Accept Hits	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Accept Hits	<input checked="" type="checkbox"/>
Global Inject	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	Global Inject	<input type="checkbox"/>
Serial Select	<input type="checkbox"/> 0 <input type="checkbox"/> 1	<input type="checkbox"/> 0 <input type="checkbox"/> 1	<input type="checkbox"/> 0 <input type="checkbox"/> 1	<input type="checkbox"/> 0 <input type="checkbox"/> 1	<input type="checkbox"/> 0 <input type="checkbox"/> 1	Serial Select	<input type="checkbox"/> 0 <input type="checkbox"/> 1
	0+1	0+1	0+1	0+1	0+1		0+1
Channel Mask	<div style="background-color: green; width: 20px; height: 20px;"></div>	<div style="background-color: green; width: 20px; height: 20px;"></div>	<div style="background-color: green; width: 20px; height: 20px;"></div>	<div style="background-color: green; width: 20px; height: 20px;"></div>	<div style="background-color: green; width: 20px; height: 20px;"></div>	Channel Mask	
	Chip 1	Chip 2	Chip 3	Chip 4	Chip 5		

Revert Changes
Read Chips
Update EEPROM
Write to Chips
Wedge FFR

2021 Beam Test

- FPHXs were operated by the Nevis-GUI.

The screenshot displays the Nevis-GUI interface for configuring the FPHX system. The interface is divided into several sections:

- Global Chip/DAQ Operations:** A grid of buttons for various operations like EFB, Enable RO, Latch FPGA, Core Reset, Start DAQ, Check GLINK, test, Init, Disable RO, Calib, JTAG Sync, Stop DAQ, Check FEM, Mask, FO Sync, Set L1, Delay, BCO Start, Global Start, Self Trig, DAC, FPGA RST, Er. EEPROM, Write Page, Read Page, Write All, Cosmic Start, and Loop.
- DAQ Configuration:** Fields for DAQ Program, NI DAQ Sample Rate (MHz), Num of events, Duration, Print Output, FPHX version, Run Number, and Filename.
- Pulsar Configuration:** Fields for Pulse amplitude, Num of Pulses, BCOs between pulses, Wedge, and Module.
- Module Enable:** A grid of checkboxes for enabling modules 0 through 14, with options for Both, Side 0, and Side 1.
- Manual Packet Send:** Fields for Packet file to send, Baud Rate, and ver7.
- Communications:** Fields for USB, Ethernet IP Addr, and Port.

The **Chip Control** section is highlighted, showing the **Channel Mask** and **Chip Side Enable** tables. The **Channel Mask** table is a 16x16 grid of red and green cells. The **Chip Side Enable** table is a 16x16 grid of 0s and 1s. The **BWSel** configuration is shown in the **Chip Command** table, where the **BWSel <7:3>** row is highlighted with a red box, showing a value of 8.

BWSel Default is set to be 8 in Nevis GUI somehow (since the original FVTX version)

FPHX Parameters

Name	Description	Default	2019 Beam Test (FVTX)	2021 Beam Test
Vref		1	1	1
DAC0		8	8	15
DAC1		16	16	30
DAC2		32	32	60
DAC3		48	48	90
DAC4		80	80	120
DAC5		112	112	150
DAC6		144	144	180
DAC7		176	176	210
N1Sel		6	6	6
N2Sel		4	4	4
FB1Sel		4	4	4
LeakSel		0	0	0
P3Sel		0	0	0
P2Sel		4	4	4
GSel	Gain Select	2	2	2
BWSel	Bandwidth Select	4	4	8
P1Sel		5	5	5
InjSel		0	0	0
LVDS Current [mA]		1	3	2

Reg	Desc	To Chip
*	Wild	0
1	Mask	0
2	Dig Ctrl	0
3	Vref	1
4	DAC0	20
5	DAC1	25
6	DAC2	30
7	DAC3	35
8	DAC4	40
9	DAC5	45
10	DAC6	50
11	DAC7	55
12	N1Sel <3:0>	6
	N2Sel <7:4>	4
13	FB1Sel <3:0>	0
	LeakSel <7:4>	0
14	P3Sel <1:0>	0
	P2Sel <7:4>	4
15	G5Sel <2:0>	2
	BWSel <7:3>	8
16	P1Sel <2:0>	5
	IngSel <5:3>	0
17	LVDS Current	0

Nevis GUI defaults
(Even from 2013)

FVFX Default (2019 Beam Test)

Side 0 Chip Settings [Editable]						Side 0 Controls		
Vref	1	1	1	1	1	Vref	1	
DAC 0	8	8	8	8	8	DAC 0	8	
DAC 1	16	16	16	16	16	DAC 1	16	
DAC 2	32	32	32	32	32	DAC 2	32	
DAC 3	48	48	48	48	48	DAC 3	48	
DAC 4	80	80	80	80	80	DAC 4	80	
DAC 5	112	112	112	112	112	DAC 5	112	
DAC 6	144	144	144	144	144	DAC 6	144	
DAC 7	176	176	176	176	176	DAC 7	176	
N1Sel	6	6	6	6	6	N1Sel	6	
N2Sel	4	4	4	4	4	N2Sel	4	
FB1Sel	4	4	4	4	4	FB1Sel	4	
LeakSel	0	0	0	0	0	LeakSel	0	
P3Sel	0	0	0	0	0	P3Sel	0	
P2Sel	4	4	4	4	4	P2Sel	4	
G5Sel	2	2	2	2	2	G5Sel	2	
BW5Sel	4	4	4	4	4	BW5Sel	4	
P1Sel	5	5	5	5	5	P1Sel	5	
InjSel	0	0	0	0	0	InjSel	0	
LVDS Current	7	7	7	7	7	LVDS Current	7	
Accept Hits	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Accept Hits	<input checked="" type="checkbox"/>	
Global Inject	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	Global Inject	<input type="checkbox"/>	
Serial Select	0	1	0	1	0	1	Serial Select	0
Channel Mask	0+1	0+1	0+1	0+1	0+1	Channel Mask	0+1	
Chip 1	Chip 2	Chip 3	Chip 4	Chip 5				

Revert Changes Read Chips Update EEPROM Write to Chips Wedge PFR

4	DAC0	15	
5	DAC1	30	
6	DAC2	60	
7	DAC3	90	
8	DAC4	120	
9	DAC5	150	
10	DAC6	180	
11	DAC7	210	

FPHX Gain Parameters

- **P1Sel<2:0>**: sets input transistor bias current = $10\mu\text{A} + [(4\mu\text{A})(\text{P1Sel})]$. Default = 101. Higher bias current gives lower noise.
- **Fb1Sel<3:0>**: sets integrator feedback transistor bias current $I_{fb} = 1.67\text{nA} + [(1.67\text{nA})(\text{Fb1Sel})]$. Default = 0100. This current defines the equivalent feedback resistance ($R_{fb} \sim 0.05/I_{fb}$), which determines the output pulse fall time (in conjunction with the programmable integrator feedback capacitor C_{fb} , yielding time constant $R_{fb}C_{fb}$).
- **N1Sel<3:0>**: Integrator source follower bias = $1.25\mu\text{A} + [(0.625\mu\text{A})(\text{N1Sel})]$. Default = 0110.
- **LeakSel<3:0>**: maximum DC input leakage current compensation = $[1.6(I_{fb}) + (3.33\text{nA})(\text{LeakSel})]$. Default = 0000.
- **GSel<2:0>**: determines integrator feedback capacitance $C_{fb} = 25\text{fF} + [(8.6\text{fF})(\text{GSel}<0>) + (25\text{fF})(\text{GSel}<1>) + (50\text{fF})(\text{GSel}<2>)]$. Default = 010.
- With a fixed shaper gain of about 5, the nominal system transfer gain can then be set to approximately 46, 50, 60, 67, 85, 100, 150, or 200 mV/fC.
- **BWSel<4:0>**: adds capacitance to the dominant node of the integrator. Explicit added capacitance = $10\text{fF} + [6\text{fF}(\text{BWSel})]$. Default = 00100. Used to compensate for the effects of varying input capacitance and gain setting on the integrator response.
- **N2Sel<3:0>**: Shaper bias current = $1\mu\text{A} + [(0.5\mu\text{A})(\text{N2Sel})]$. Default = 0100. This is used to set the bandwidth of the shaper, which determines the output pulse rise time (peaking time). A shaper bias of $3.5\mu\text{A}$ results in a peaking time of approximately 60ns. Higher settings result in faster peaking times.
- **P2Sel<3:0>**: Comparator bias current = $0.5\mu\text{A} + [(0.25\mu\text{A})(\text{P2Sel})]$. Default = 0100. Higher settings reduce comparator delay.
- **P3Sel<1:0>**: Comparator second stage pullup bias current. Default = 00. Mainly affects comparator trailing edge delay – higher settings reduce the delay.
- **InjSel<2:0>**: Digital inject circuit DAC setting. Charge inject magnitude = $(1\text{Ke})(\text{InjSel} + 1)$. Default = 000 (1Ke).
- **Vref<1:0>**: Shaper DC reference voltage = $150\text{mV} + [(60\text{mV})(\text{Vref}<1:0>)]$. Default = 01. For maximum dynamic range, set **Vref** as low as possible while still maintaining linearity.
- **Vth0<7:0>** (Threshold ADC 0): 0th ADC comparator (discriminator) threshold = $V_{ref} + [(4\text{mV})(\text{Vth0})]$. Default $V_{th0}<7:0> = 00001000 (V_{ref} + 32\text{mV})$.
- **Vth1<7:0>**: 1st ADC comparator threshold = $V_{ref} + [(4\text{mV})(\text{Vth1})]$. Default $V_{th1}<7:0> = 00010000 (V_{ref} + 64\text{mV})$.
- **Vth2<7:0>**: 2nd ADC comparator threshold = $V_{ref} + [(4\text{mV})(\text{Vth2})]$. Default $V_{th2}<7:0> = 00100000 (V_{ref} + 128\text{mV})$.
- **Vth3<7:0>**: 3rd ADC comparator threshold = $V_{ref} + [(4\text{mV})(\text{Vth3})]$. Default $V_{th3}<7:0> = 00110000 (V_{ref} + 192\text{mV})$.
- **Vth4<7:0>**: 4th ADC comparator threshold = $V_{ref} + [(4\text{mV})(\text{Vth4})]$. Default $V_{th4}<7:0> = 01010000 (V_{ref} + 320\text{mV})$.

• **GSel<2:0>** Def=010

$$C_{fb}[fF] = 25 + 8.6 \cdot G\text{Sel}\langle 0 \rangle + 25 \cdot G\text{Sel}\langle 1 \rangle + 50 \cdot G\text{Sel}\langle 2 \rangle$$

• **BWSel<4:0>** Def=00100

$$C_{add}[fF] = 10 + 6 \cdot BW\text{Sel}$$

Total Capacitance

$$C_{Total} = C_{fb} + C_{add} \quad ?$$

FPHX Integrator Schematic

- A new type of continuous reset and leakage compensation circuit has been designed for the integrator. In Figure 6, a programmable current labeled I_{fb} sets the effective reset resistance. M_{fb} acts exactly like a resistor of value $1/g_m$ for small signals, where g_m depends directly on I_{fb} since M_{fb} is in weak inversion. This programmed resistance, in conjunction with the feedback capacitor, sets the RC fall time (return to baseline) of the shaped signal. For large signals, when the output swings more than a hundred mV or so, M_{fb} no longer looks like a resistor, but a constant current source. The return to baseline then becomes linear until the output approaches the reset level, at which point it becomes an exponential RC decay again.

Simplified conceptual diagram of one channel

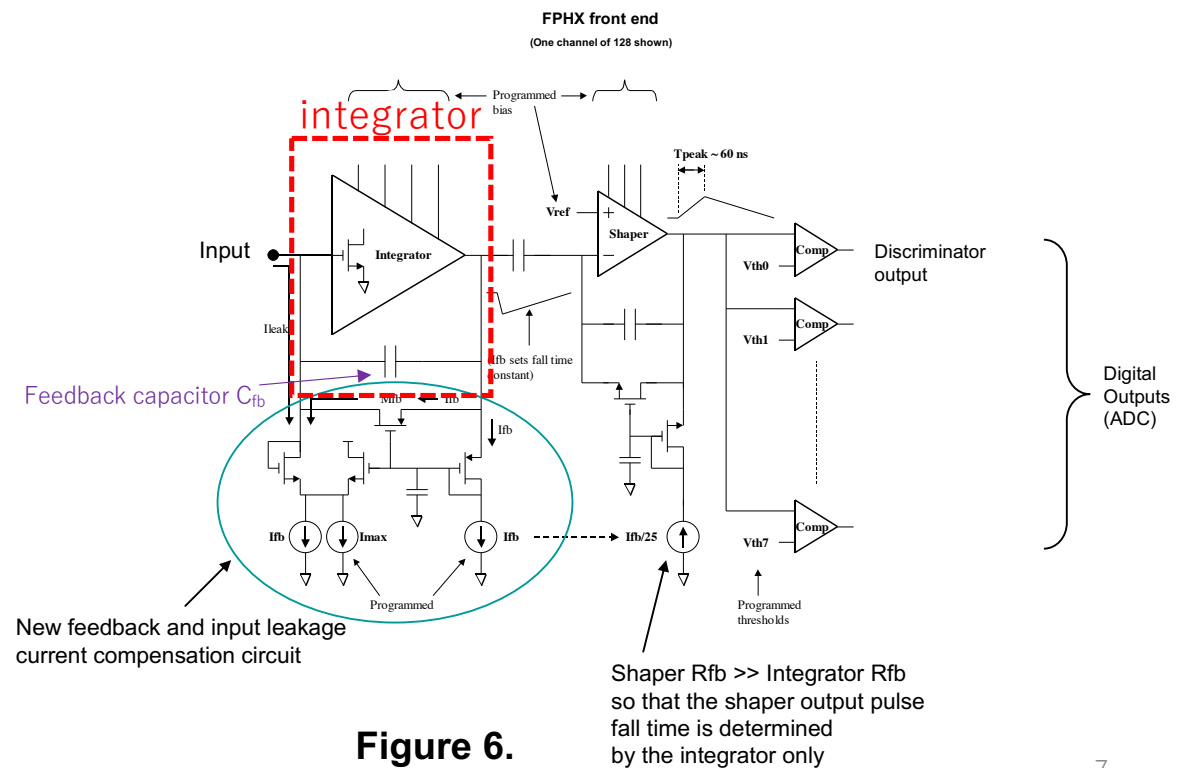


Figure 6.

FPHX Integrator Schematic

- The integrator is shown in detail in Figure 7. The input transistor feeds a regulated cascode (to keep the open loop gain high), and is biased by a cascode current source. Additional input transistor bias current is programmed through switched current sources. The integrator bandwidth is adjustable via switched capacitors on the amplifier dominant node. The transfer gain is set with programmable feedback capacitors. A source follower drives the integrator output.

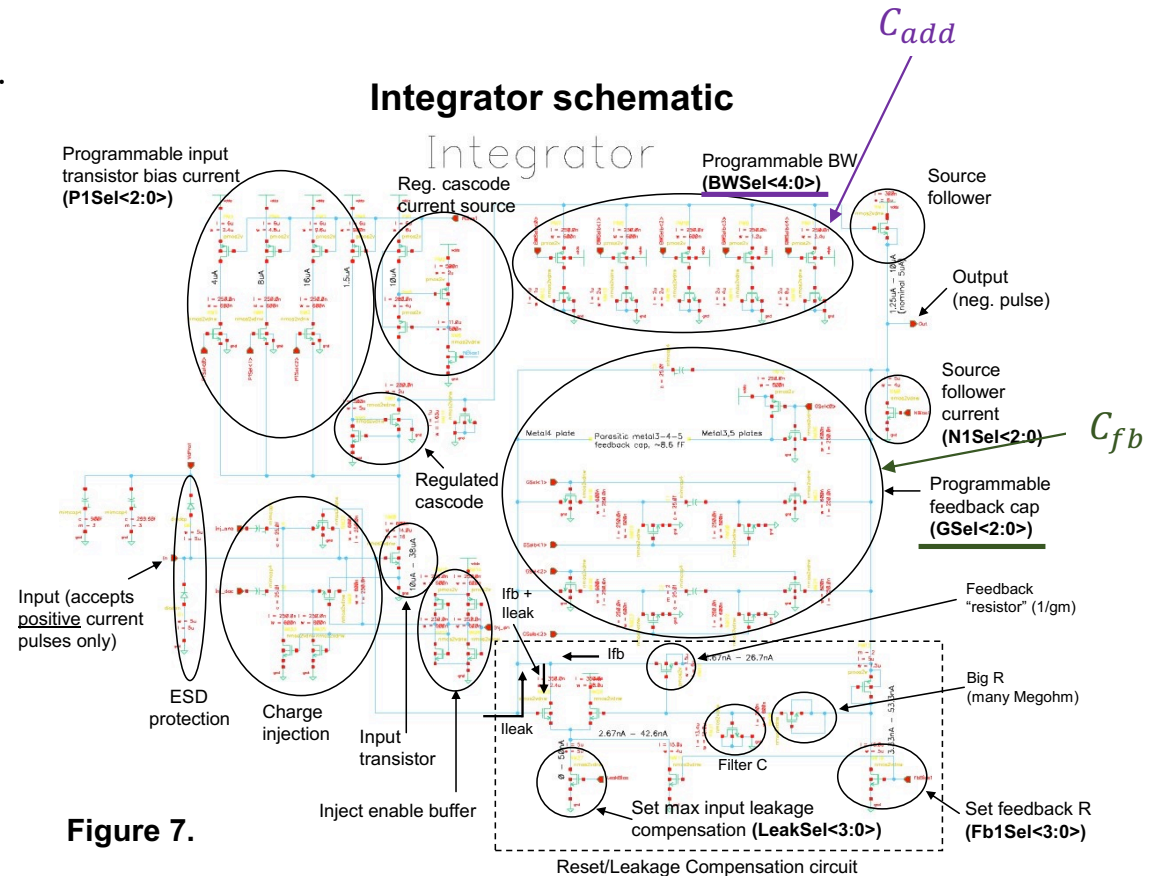
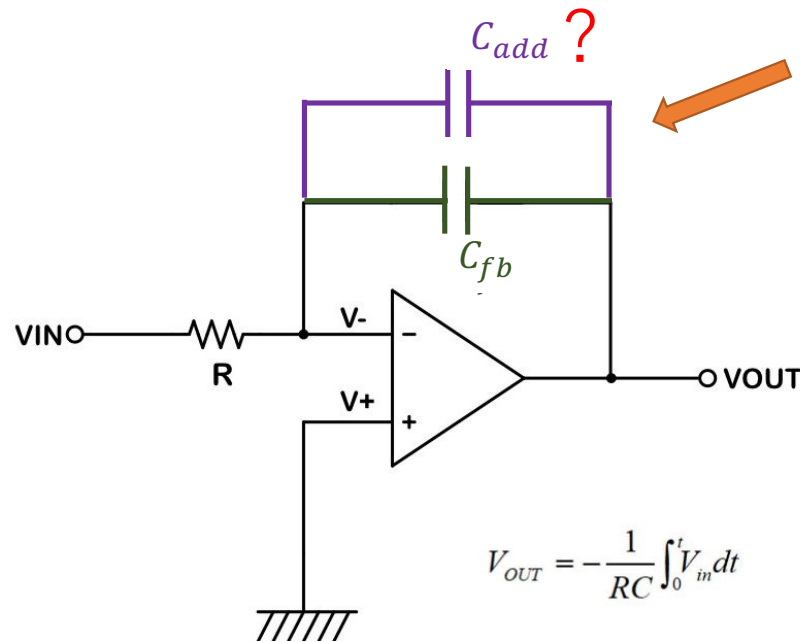
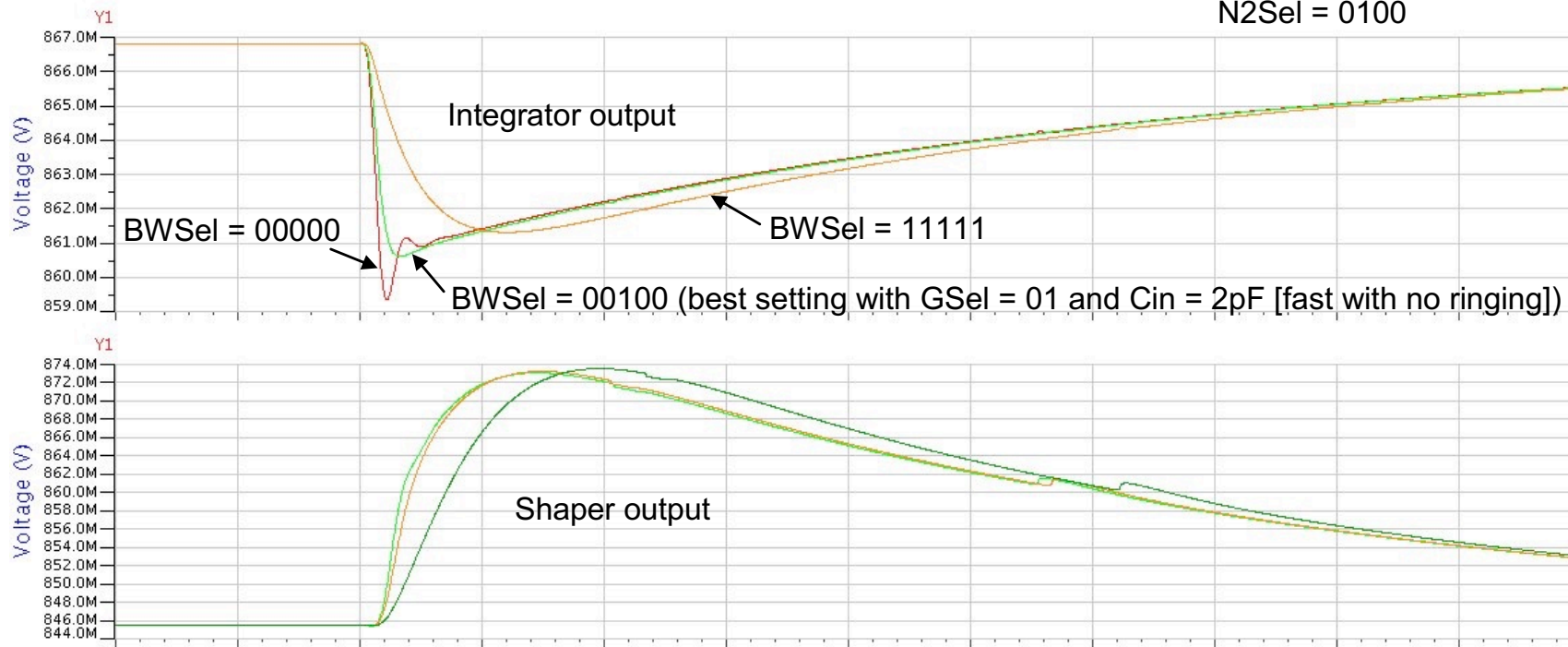


Figure 7.

Effect of BWSel Parameter

Effect of BWSel parameter on integrator response

Qin = 2000e
Cin = 2pF (total)
GSel = 010
Fb1Sel = 0100
N2Sel = 0100



FPHX Gain Calculation

- GSel<2:0> Def=010

$$C_{fb}[fF] = 25 + 8.6 \cdot GSel\langle 0 \rangle + 25 \cdot GSel\langle 1 \rangle + 50 \cdot GSel\langle 2 \rangle$$

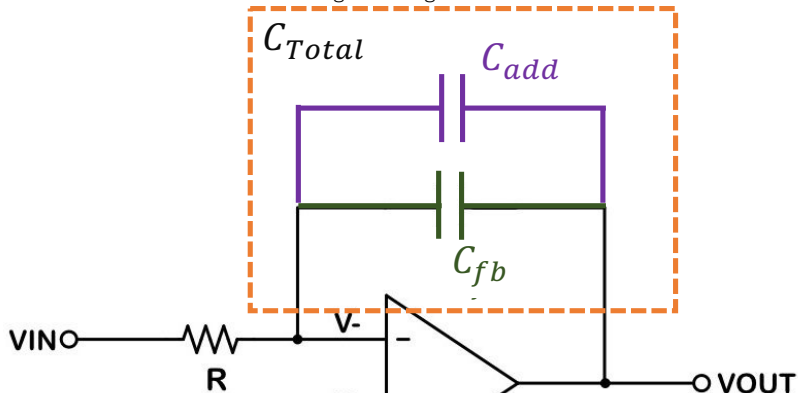
- BWSel<4:0> Def=00100

$$C_{add}[fF] = 10 + 6 \cdot BWSel$$

Total Capacitance

$$C_{Total} = C_{fb} + C_{add}$$

Assuming following circuit is correct



Beam Test	2019	2021
GSel	2 <010>	2 <010>
BWSel	4 <00100>	8 <01000>
$C_{fb}[fF]$	25+25=50	25+25=50
$C_{add}[fF]$	10+6•4=34	10+6•8=58
$C_{total}[fF]$	84	108
$V_{out}[a.u.]$	1	0.78

$$V_{OUT} = -\frac{1}{RC} \int_0^t V_{in} dt$$

Observation

$$\frac{MIP_{2021BT}}{MIP_{2019BT}} = \frac{75}{118} \sim 0.63$$

Still not sufficient

Global Start

Initialization Sequence

```
def global_start_daq_prog():
    send_fo_sync()
    send_fpga_reset()
    time.sleep(2)
    #send_fo_sync()
    send_reset(regpanels)
    send_init(regpanels)
    send_enable_ro(regpanels)
    send_latch()
    #send_latch()
    send_fem_lv11_delay(int(fem_lv11_delay_var.get()))
    send_pulse_module(int(pulse_module_var.get()),int(pulse_wedge_var.get()), f(int(femaddr_var.get())))
    send_bco_start()
    send_calib()
    start_daq_prog(regpanels)
```

```
def send_init(self,wedgeaddr,femaddr):
    # chip ID
    chipid = int(self.chipid)

    print 'ChipConfig.send_init: Send init for chip %d' % (int(self.chipid))

    # Register addresses
    regs = [ 1, 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, 13, 14, 15, 16, 17 ]

    # Which operation to perform on each register (1=Write, 2=Set, etc. cf. FPHX manual)
    ops = [ 2, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1 ]

    # Here are the values to send for each register
    vals = [ 128, # Global mask all channels
             int(self.reg_vals[1].get()), # The reset we initialize from the corresponding values
             int(self.reg_vals[2].get()),
             int(self.reg_vals[3].get()),
             int(self.reg_vals[4].get()),
             int(self.reg_vals[5].get()),
             int(self.reg_vals[6].get()),
             int(self.reg_vals[7].get()),
             int(self.reg_vals[8].get()),
             int(self.reg_vals[9].get()),
             int(self.reg_vals[10].get()),
             int(self.reg_vals2[11].get())<<4 | int(self.reg_vals[11].get()),
             int(self.reg_vals2[12].get())<<4 | int(self.reg_vals[12].get()),
             int(self.reg_vals2[13].get())<<4 | int(self.reg_vals[13].get()),
             int(self.reg_vals2[14].get())<<3 | int(self.reg_vals[14].get()),
             int(self.reg_vals2[15].get())<<3 | int(self.reg_vals[15].get()),
             int(self.reg_vals[16].get())
           ]

    length = int(17*4) # 17 commands
    dest = TESTBENCH_FPHX # destination == 'to FPHX'

    print "Chip %d WedgeAddr 0x%02X:" % (chipid,(lambda:wedgeaddr if wedgeaddr else 0)())
    #for r, o, v in zip(regs,ops,vals):
    #    print "Register %d: oper %d with val %d" % (r,o,v)

    datalen = length
    data = create_string_buffer(datalen)
    offset = 0

    for i in range(0,17) :
        word = make_fphx_cmd(chipid,regs[i],ops[i],vals[i])
        struct.pack_into(">I",data,offset,word)
        offset += 4

    # if use_roc.get(): wedgeaddr = (0xF & self.moduleid) | (0xF & iside)<<4
    if use_roc.get(): wedgeaddr = (0xFF)
    femaddr = None
    if use_roc.get() == 2: femaddr = femaddr_var.get()

    buf = create_packet(dest,data.raw,wedgeaddr,femaddr)

    print 'ChipConfig.send_init: Send init packet = %s' % hexify_bytes(buf)
    write_bytes_to_target(buf.raw,comm_panel.getTarget())

    # Now send down the enable mask
    self.send_mask(wedgeaddr,femaddr)

    return
```

BWSEL

Reg	Desc	To Chip
*	Wild	0
1	Mask	0
2	Dig Ctrl	5
3	Vref	1
4	DAC0	20
5	DAC1	25
6	DAC2	30
7	DAC3	35
8	DAC4	40
9	DAC5	45
10	DAC6	50
11	DAC7	55
12	N1Sel <3:0>	6
	N2Sel <7:4>	4
13	FB1Sel <3:0>	4
	LeakSel <7:4>	0
14	P3Sel <1:0>	0
	P2Sel <7:4>	4
15	GSel <2:0>	2
	BWSEL <7:3>	8
16	P1Sel <2:0>	5
	InjSel <5:3>	0
17	LVDS Current	3

Are the parameters automatically loaded to FPHX at the beginning of run?

Sending parameters routine?

To be confirmed

- FPHX operation conditions for 2019 and 2021 beam tests.
 - Does default parameters in Nevis-GUI really loaded to FPHX automatically in the initialization routine of the global start?
- Integrator circuit. If $C_{Total} = C_{fb} + C_{add}$ is correct.
- Actual measurement and comparison of MIP position BWSel=4 vs BWSel=8 is mandatory to observe the actual response.

Programming Strategy

- First determine **GSel** based on the desired approximate transfer gain (approx. 50 – 200 mV/fC).
- Then depending on the value of the input capacitance (C_{in}), program **BWSel** to achieve fast integrator response without ringing.

- For $C_{in} = 2$ pF (1.5 pF detector + 0.5 pF parasitic):

- If **GSel** = 000, set **BWSel** = 00000
- If **GSel** = 010, set **BWSel** = 00100
- If **GSel** = 100, set **BWSel** = 01000
- If **GSel** = 110, set **BWSel** = 01100

Physics	Dec	Bin
GSel	2	010
BWSel	4	1000

Relevant setting for INTT

- For $C_{in} = 1.5$ pF (1 pF detector + 0.5 pF parasitic):

- If **GSel** = 000, set **BWSel** = 00001
- If **GSel** = 010, set **BWSel** = 00110
- If **GSel** = 100, set **BWSel** = 01010
- If **GSel** = 110, set **BWSel** = 01110

- For $C_{in} = 1$ pF (0.5 pF detector + 0.5 pF parasitic):

- If **GSel** = 000, set **BWSel** = 00010
- If **GSel** = 010, set **BWSel** = 01000
- If **GSel** = 100, set **BWSel** = 01110
- If **GSel** = 110, set **BWSel** = 10101

Nevis	Dec	Bin
GSel	2	010
BWSel	8	1000

- Program **Fb1Sel** based on the desired fall time constant
- Then program **N2Sel** to achieve the desired rise time/peaking time (rise and fall times will have some effect on the transfer gain)
- Program **Vref** to the lowest value possible that allows linear response (nominally 00)
- Based on the transfer gain, set the desired comparator thresholds

FVTX NIM

between columns is 100 μm and is completely neutral.

The strip length increases with radius on the sensor, and goes from 3.4 mm at the inner radius to 11.5 mm at the outer radius, with a pitch of 75 μm in the radial direction. Each sensor covers 7.5° in ϕ , and since the strips are perpendicular to the radius, they make an angle of 86.25° with respect to the centerline, as can be seen in [Fig. 4](#).

The data words are output over two LVDS serial lines at up to 200 MHz clock rate. The total power consumption of the FPHX is $\sim 390 \mu\text{W}$ per channel. The noise, when the chip was wire bonded to a sensor with strips $\sim 2\text{--}11$ mm in length ($\sim 1\text{--}2.5$ pF), was simulated and measured to be below the design specification of 500 electrons.

INTT Type-A $\sim 2.5\text{pF}$ (78 μm , 12mm)
Type-B $\sim 3\text{pF}$ or so?